

Notice of References Cited

Application/Control No.

10/570,820

Applicant(s)/Patent Under

Reexamination

SINGLETON, MARK JAMES

Examiner

JAMES J. BUCKLE JR

Art Unit

3633

Page 1 of 3

U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-697,746 A	04-1902	Pierson	52/417
*	B US-697,747 A	04-1902	Peirson	52/417
*	C US-781,538 A	01-1905	Lyster	52/461
*	D US-850,275 A	04-1907	Staples	52/584.1
*	E US-1,219,177 A	03-1917	Silverman	52/395
*	F US-2,803,321 A	08-1957	JACK FOX-WILLIAMS	52/464
*	G US-2,822,898 A	02-1958	RICHARDS ARCHER W	52/471
*	H US-2,855,871 A	10-1958	HUNTINGTON GLEN H	52/461
*	I US-2,907,287 A	10-1959	TROSTLE JOHN W	52/463
*	J US-3,225,502 A	12-1965	WALTER HALLAUEER	52/461
*	K US-3,332,190 A	07-1967	ROBERT EKSTROM	52/464
*	L US-3,363,381 A	01-1968	FORREST RONALD C	52/464
*	M US-3,381,436 A	05-1968	BARTON ELLIOTT NORMAN et al.	52/468

FOREIGN PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N	JP 02173408 A	07-1990	Japan	HARIKI et al.	F16B 05/12
O					
P					
Q					
R					
S					
T					

NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
U	
V	
W	
X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a))
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited

Application/Control No.

10/570,820

Applicant(s)/Patent Under

Reexamination

SINGLETON, MARK JAMES

Examiner

JAMES J. BUCKLE JR

Art Unit

3633

Page 2 of 3

U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-3,594,028 A	07-1971	Scott, Victor P.	52/465
*	B US-3,667,183 A	06-1972	Heirich, William C.	52/506.06
*	C US-3,958,388 A	05-1976	Hawes, Turner C.	52/584.1
*	D US-4,038,796 A	08-1977	Eckel, Alan	52/220.7
*	E US-4,106,255 A	08-1978	Eckel, Alan	52/586.1
*	F US-4,569,175 A	02-1986	Abciuk, Pinhas	52/506.07
*	G US-4,583,339 A	04-1986	Cotter, Donald P.	52/466
*	H US-4,603,528 A	08-1986	Sigerist, Helmut	52/464
*	I US-4,627,469 A	12-1986	Buard, Yvon	138/92
*	J US-4,829,740 A	05-1989	Hutchison, Douglas	52/475.1
*	K US-4,833,858 A	05-1989	Hutchison, Douglas	52/475.1
*	L US-4,930,279 A	06-1990	Bart et al.	52/466
*	M US-5,370,344 A	12-1994	Nadhermy, Rudolph E.	248/56

FOREIGN PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N				
*	O				
*	P				
*	Q				
*	R				
*	S				
*	T				

NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U
*	V
*	W
*	X

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a))
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited

Application/Control No.

10/570,820

Applicant(s)/Patent Under

Reexamination

SINGLETON, MARK JAMES

Examiner

JAMES J. BUCKLE JR

Art Unit

3633

Page 3 of 3

U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-5,511,353 A	04-1996	Jones, Stephen L.	52/536
*	B US-5,735,096 A	04-1998	Krass, Reinaldo	52/464
*	C US-5,743,498 A	04-1998	Kampf, Mark	248/74.4
*	D US-5,857,799 A	01-1999	Blake, III, Thomas E.	403/292
*	E US-6,092,346 A	07-2000	Even et al.	52/579
*	F US-2002/0032997 A1	03-2002	Shreiner, Thomas A.	52/393
*	G US-6,453,632 B1	09-2002	Huang, Chin-Chih	52/403.1
*	H US-6,536,175 B2	03-2003	Conterno, Cosimo	52/489.1
*	I US-7,562,504 B2	07-2009	Herbst et al.	52/461
J	US-			
K	US-			
L	US-			
M	US-			

FOREIGN PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N					
O					
P					
Q					
R					
S					
T					

NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
U	
V	
W	
X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a))
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.